


Search Notes 	Application/Control No. 10781985	Applicant(s)/Patent Under Reexamination MAHLAB ET AL.
	Examiner Kim, David S	Art Unit 2613

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
EAST search - see search history printout	11/27/2006	DSK, 12/5 - 12/7/06
text search in 398/25-38	11/27/2006	DSK, 12/7/06
scholar.google.com - various combinations of the following terms: measuring chirp nonlinearity ber monitor dispersion nonlinear effect measure compensate bit rate reroute regeneration detect sense determine self-phase self phase spm four-wave four photon fwm cross-phase cross phase cpm xpm brillouin raman stokes	11/27/2006	DSK, 12/5 - 12/7/06
text search in 398/25, 33, 147, 158, 159	12/7/2006	DSK
ieeexplore.ieee.org - various combinations of the following terms: measur* detect* sens* monitor* determin* chirp nonlinear* non-linear* optic*	12/7/2006	DSK
discussed claim 2 with SPE Jason Chan, PE Christina Leung, PE Leslie Pascal, PE Mohammad Sedighian	12/7/2006	DSK

INTERFERENCE SEARCH			
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